

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	91	(prevent\$4 or stop\$4) near10 reset near10 float\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:55
L2	74	1 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:55
L3	2449526	(integrated adj circuit\$1) or chip\$1 or memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 13:04
L4	34	2 and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 13:04
S1	4613	reset\$4 near10 (circuit\$1 or chip\$1 or device\$1) near10 external\$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:17
S2	62085	"365"/\$7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 14:27
S3	639	S1 and S2 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:55
S4	1710295	test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 14:33
S5	349	S3 and S4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 14:28

S6	535	reset\$3 near10 (voltage\$1 or potential\$1) near10 test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 19:39
S7	89	S2 and S6 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 19:40
S14	765	reset\$3 near20 (voltage\$1 or potential\$1) near20 test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:14
S15	128	S2 and S14 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:14
S16	39	S15 not S7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 19:40
S17	68	reset\$3 near20 bias near20 test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:13
S18	808	reset\$3 near20 (voltage\$1 or potential\$1 or bias) near20 test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:14
S19	657	S18 and @ad<"20020529"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:15
S20	529	S19 not S15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:15
S21	133954	reset\$4 near10 (circuit\$1 or chip\$1 or device\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:19

S22	336	S20 and S21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:17
S23	299568	test\$4 near10 (circuit\$1 or chip\$1 or device\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:19
S24	296	S22 and S23	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/10 20:31
S27	2447534	(integrated adj circuit\$1) or chip\$1 or memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/11 12:56